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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/807,239	TOMITA ET AL.	
Examiner	Art Unit	
Long Pham	2814	

	CEAD	CHED	
	SEAR	CHED	
Class	Subclass	Date	Examiner
257	529,758	7/24/2006	LP
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INT	ERFERENC	RFERENCE SEARCHED	
Class	Subclass	Date	Examiner
257	529	7/24/2006	LP
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated text or interference searches	7/24/2006	LP